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Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

Product Status	Active
Core Processor	e200z0h
Core Size	32-Bit Single-Core
Speed	64MHz
Connectivity	CANbus, I ² C, LINbus, SCI, SPI
Peripherals	DMA, POR, PWM, WDT
Number of I/O	79
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	64K x 8
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 28x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/spc5604bk0vll6r

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Table 2. MPC5604B/C device comparison¹

	Device											
Feature	SPC560B 40L1	SPC560B 40L3	SPC560B 40L5	SPC560C 40L1	SPC560C 40L3	SPC560B 50L1	SPC560B 50L3	SPC560B 50L5	SPC560C 50L1	SPC560C 50L3	SPC560B 50B2	
CPU						e200z0h						
Execution speed ²					Stat	tic – up to 64	MHz					
Code Flash			256 KB					512	2 KB			
Data Flash					64	KB (4 × 16	KB)					
RAM		24 KB		32	KB		32 KB			48 KB		
MPU				I		8-entry						
ADC (10-bit)	12 ch	28 ch	36 ch	8 ch	28 ch	12 ch	28 ch	36 ch	8 ch	28 ch	36 ch	
СТИ		Yes										
Total timer I/O ³ eMIOS	12 ch, 16-bit	28 ch, 16-bit	56 ch, 16-bit	12 ch, 16-bit	28 ch, 16-bit	12 ch, 16-bit	28 ch, 16-bit	56 ch, 16-bit	12 ch, 16-bit	28 ch, 16-bit	56 ch, 16-bit	
• PWM + MC + IC/OC ⁴	2 ch	5 ch	10 ch	2 ch	5 ch	2 ch	5 ch	10 ch	2 ch	5 ch	10 ch	
• PWM + IC/OC ⁴	10 ch	20 ch	40 ch	10 ch	20 ch	10 ch	20 ch	40 ch	10 ch	20 ch	40 ch	
• IC/OC ⁴	_	3 ch	6 ch	_	3 ch	—	3 ch	6 ch	_	3 ch	6 ch	
SCI (LINFlex)		3 ⁵						4				
SPI (DSPI)	2	:	3	2	3	2	:	3	2		3	
CAN (FlexCAN)		2 ⁶		5	6	37			5	6		
l ² C						1						
32 kHz oscillator						Yes						
GPIO ⁸	45	79	123	45	79	45	79	123	45	79	123	
Debug		<u>l</u>	1	1	JT	AG	1	1	1	1	Nexus2+	
Package	LQFP64 ⁹	LQFP100	LQFP144	LQFP64 ⁹	LQFP100	LQFP64 ⁹	LQFP100	LQFP144	LQFP64 ⁹	LQFP100	LBGA208 ¹⁰	

¹ Feature set dependent on selected peripheral multiplexing—table shows example implementation
 ² Based on 125 °C ambient operating temperature
 ³ See the eMIOS section of the device reference manual for information on the channel configuration and functions.

⁴ IC – Input Capture; OC – Output Compare; PWM – Pulse Width Modulation; MC – Modulus counter

⁵ SCI0, SCI1 and SCI2 are available. SCI3 is not available.

Freescale Semiconductor

MPC5604B/C Microcontroller Data Sheet, Rev. 11

Introduction

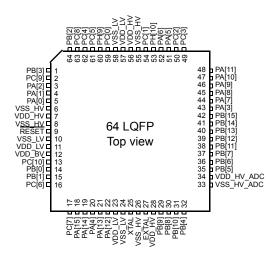


Figure 2. MPC560xB LQFP 64-pin configuration

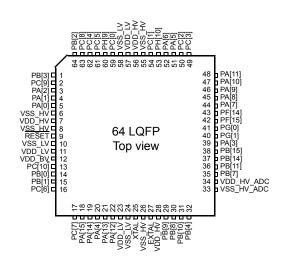
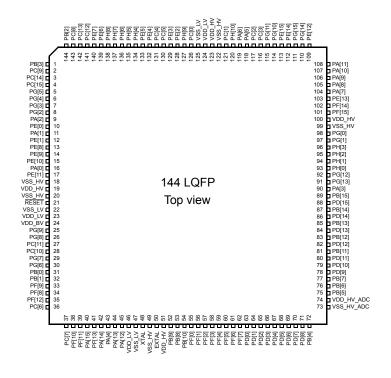
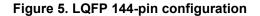


Figure 3. MPC560xC LQFP 64-pin configuration

Package pinouts and signal descriptions



Note: Availability of port pin alternate functions depends on product selection.



		-					uo		Pir	num	ber	
Port pin	PCR	Alternate function ¹	Function	Peripheral	I/O direction ²	Pad type	RESET configuration	MPC560xB 64 LQFP	MPC560xC 64 LQFP	100 LQFP	144 LQFP	208 MAPBGA ³
PD[1]	PCR[49]	AF0 AF1 AF2 AF3 —	GPIO[49] — — GPI[5]	SIUL — — ADC	 - 	Ι	Tristate	_	_	42	64	T12
PD[2]	PCR[50]	AF0 AF1 AF2 AF3 —	GPIO[50] - - GPI[6]	SIUL — — ADC	 - 	-	Tristate	_	_	43	65	R12
PD[3]	PCR[51]	AF0 AF1 AF2 AF3 —	GPI0[51] — — GPI[7]	SIUL — — ADC	 	Ι	Tristate			44	66	P13
PD[4]	PCR[52]	AF0 AF1 AF2 AF3 —	GPI0[52] — — — GPI[8]	SIUL — — ADC	 - - 	I	Tristate	_	_	45	67	R13
PD[5]	PCR[53]	AF0 AF1 AF2 AF3 —	GPIO[53] — — — GPI[9]	SIUL — — ADC	 - 	Ι	Tristate	_	_	46	68	T13
PD[6]	PCR[54]	AF0 AF1 AF2 AF3 —	GPIO[54] GPI[10]	SIUL — — — ADC	 - - 	I	Tristate	_	_	47	69	T14
PD[7]	PCR[55]	AF0 AF1 AF2 AF3 —	GPIO[55] — — — GPI[11]	SIUL — — — ADC	 - - 	I	Tristate	_	_	48	70	R14
PD[8]	PCR[56]	AF0 AF1 AF2 AF3 —	GPIO[56] — — — GPI[12]	SIUL — — ADC	 - 	Ι	Tristate			49	71	T15

Table 6. Functional port pin descriptions (continued)

							uo		Pir	n num	ber	
Port pin	PCR	Alternate function ¹	Function	Peripheral	I/O direction ²	Pad type	RESET configuration	MPC560xB 64 LQFP	MPC560xC 64 LQFP	100 LQFP	144 LQFP	208 MAPBGA ³
PF[2]	PCR[82]	AF0 AF1 AF2 AF3 —	GPIO[82] E0UC[12] CS0_2 — ANS[10]	SIUL eMIOS_0 DSPI_2 — ADC	I/O I/O I/O I	J	Tristate				57	T10
PF[3]	PCR[83]	AF0 AF1 AF2 AF3 —	GPIO[83] E0UC[13] CS1_2 — ANS[11]	SIUL eMIOS_0 DSPI_2 — ADC	/O /O 0 	J	Tristate	_	—	_	58	R10
PF[4]	PCR[84]	AF0 AF1 AF2 AF3 —	GPIO[84] E0UC[14] CS2_2 — ANS[12]	SIUL eMIOS_0 DSPI_2 — ADC	I/O I/O O I	J	Tristate	_	_	_	59	N11
PF[5]	PCR[85]	AF0 AF1 AF2 AF3 —	GPIO[85] E0UC[22] CS3_2 — ANS[13]	SIUL eMIOS_0 DSPI_2 — ADC	I/O I/O O I	J	Tristate	_	_	_	60	P11
PF[6]	PCR[86]	AF0 AF1 AF2 AF3 —	GPIO[86] E0UC[23] — ANS[14]	SIUL eMIOS_0 — ADC	/O /O 	J	Tristate	_	_	_	61	T11
PF[7]	PCR[87]	AF0 AF1 AF2 AF3 —	GPIO[87] — — — ANS[15]	SIUL — — — ADC	I/O — — — I	J	Tristate	_	—	_	62	R11
PF[8]	PCR[88]	AF0 AF1 AF2 AF3	GPIO[88] CAN3TX ¹⁴ CS4_0 CAN2TX ¹⁵	SIUL FlexCAN_3 DSPI_0 FlexCAN_2	I/O O O	М	Tristate		_		34	P1
PF[9]	PCR[89]	AF0 AF1 AF2 AF3 —	GPIO[89] — CS5_0 — CAN2RX ¹⁵ CAN3RX ¹⁴	SIUL DSPI_0 FlexCAN_2 FlexCAN_3	I/O — 0 — I I	S	Tristate				33	N2

Table 6. Functional port pin descriptions (continued)

		-					u		Pin	num	ber	
Port pin	PCR	Alternate function ¹	Function	Peripheral	I/O direction ²	Pad type	RESET configuration	MPC560xB 64 LQFP	MPC560xB 64 LQFP MPC560xC 64 LQFP		144 LQFP	208 MAPBGA ³
PH[4]	PCR[116]	AF0 AF1 AF2 AF3	GPIO[116] E1UC[6] — —	SIUL eMIOS_1 —	I/O I/O 	Μ	Tristate				134	A6
PH[5]	PCR[117]	AF0 AF1 AF2 AF3	GPIO[117] E1UC[7] — —	SIUL eMIOS_1 —	I/O I/O —	S	Tristate				135	B6
PH[6]	PCR[118]	AF0 AF1 AF2 AF3	GPIO[118] E1UC[8] — MA[2]	SIUL eMIOS_1 ADC	I/O I/O — O	М	Tristate				136	D5
PH[7]	PCR[119]	AF0 AF1 AF2 AF3	GPIO[119] E1UC[9] CS3_2 MA[1]	SIUL eMIOS_1 DSPI_2 ADC	I/O I/O O O	М	Tristate				137	C5
PH[8]	PCR[120]	AF0 AF1 AF2 AF3	GPIO[120] E1UC[10] CS2_2 MA[0]	SIUL eMIOS_1 DSPI_2 ADC	I/O I/O O O	М	Tristate	l	_		138	A5
PH[9] ⁹	PCR[121]	AF0 AF1 AF2 AF3	GPIO[121] — TCK —	SIUL — JTAGC —	I/O 	S	Input, weak pull-up	60	60	88	127	B8
PH[10] ⁹	PCR[122]	AF0 AF1 AF2 AF3	GPIO[122] — TMS —	SIUL — JTAGC —	I/O — I —	S	Input, weak pull-up	53	53	81	120	B9

Table 6. F	unctional	port pin	descriptions	(continued)
				(

¹ Alternate functions are chosen by setting the values of the PCR.PA bitfields inside the SIUL module. PCR.PA = 00 → AF0; PCR.PA = 01 → AF1; PCR.PA = 10 → AF2; PCR.PA = 11 → AF3. This is intended to select the output functions; to use one of the input functions, the PCR.IBE bit must be written to '1', regardless of the values selected in the PCR.PA bitfields. For this reason, the value corresponding to an input only function is reported as "—".

² Multiple inputs are routed to all respective modules internally. The input of some modules must be configured by setting the values of the PSMIO.PADSELx bitfields inside the SIUL module.

³ 208 MAPBGA available only as development package for Nexus2+

⁴ All WKPU pins also support external interrupt capability. See wakeup unit chapter for further details.

⁵ NMI has higher priority than alternate function. When NMI is selected, the PCR.AF field is ignored.

⁶ "Not applicable" because these functions are available only while the device is booting. Refer to BAM chapter of the reference manual for details. ¹ Default manufacturing value is '1'. Value can be programmed by customer in Shadow Flash.

3.11.2 NVUSRO[OSCILLATOR_MARGIN] field description

The fast external crystal oscillator consumption is dependent on the OSCILLATOR_MARGIN bit value. Table 10 shows how NVUSRO[OSCILLATOR_MARGIN] controls the device configuration.

Table 10. OSCILLATOR_MARGIN field description

Value ¹	Description
0	Low consumption configuration (4 MHz/8 MHz)
1	High margin configuration (4 MHz/16 MHz)

Default manufacturing value is '1'. Value can be programmed by customer in Shadow Flash.

3.11.3 NVUSRO[WATCHDOG_EN] field description

The watchdog enable/disable configuration after reset is dependent on the WATCHDOG_EN bit value. Table 11 shows how NVUSRO[WATCHDOG_EN] controls the device configuration.

Table 11. WATCHDOG_EN field description

Value ¹	Description
0	Disable after reset
1	Enable after reset

¹ Default manufacturing value is '1'. Value can be programmed by customer in Shadow Flash.

 $^2~$ CL includes device and package capacitances (C_{PKG} < 5 pF).

3.15.5 I/O pad current specification

The I/O pads are distributed across the I/O supply segment. Each I/O supply segment is associated to a V_{DD}/V_{SS} supply pair as described in Table 22.

Package	Supply segment									
	1	2	3	4	5	6				
208 MAPBGA ¹	Equivale	ent to 144 LQFP	tribution	МСКО	MDOn/MSEO					
144 LQFP	pin20–pin49	pin51–pin99	pin100-pin122	pin 123-pin19	_	—				
100 LQFP	pin16–pin35	pin37–pin69	pin70–pin83	pin 84–pin15	_	—				
64 LQFP	pin8–pin26	pin28–pin55	pin56–pin7	_	_	—				

Table 22. I/O supply segment

¹ 208 MAPBGA available only as development package for Nexus2+

Table 23 provides I/O consumption figures.

In order to ensure device reliability, the average current of the I/O on a single segment should remain below the I_{AVGSEG} maximum value.

Symbo	ı	С	Parameter	Condi	tions ¹		Value		Unit
Symbo	1	U	Farameter	Cond		Min	Тур	Мах	Onit
I _{SWTSLW} ,2	СС	D	Dynamic I/O current for SLOW configuration	C _L = 25 pF	V _{DD} = 5.0 V ± 10%, PAD3V5V = 0			20	mA
					V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	_	_	16	
I _{SWTMED} ²	СС	D	Dynamic I/O current for MEDIUM configuration	C _L = 25 pF	V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	_	_	29	mA
					V _{DD} = 3.3 V ± 10%, PAD3V5V = 1		—	17	
I _{SWTFST} ²	СС	D	Dynamic I/O current for FAST configuration	C _L = 25 pF	V _{DD} = 5.0 V ± 10%, PAD3V5V = 0		—	110	mA
					V _{DD} = 3.3 V ± 10%, PAD3V5V = 1		—	50	
I _{RMSSLW}	СС	D	Root mean square I/O	C _L = 25 pF, 2 MHz	$V_{DD} = 5.0 V \pm 10\%$,	_		2.3	mA
			current for SLOW configuration	C _L = 25 pF, 4 MHz	PAD3V5V = 0	_	—	3.2	
			-	C _L = 100 pF, 2 MHz		_	_	6.6	
				C _L = 25 pF, 2 MHz	$V_{DD} = 3.3 V \pm 10\%$,		—	1.6	
				C _L = 25 pF, 4 MHz	PAD3V5V = 1	_		2.3	
				C _L = 100 pF, 2 MHz		_		4.7	

Table 23. I/O consumption

•					144/100) LQFP			64 L	QFP	
Sup	ply seg	ment	Pad	Weigh	nt 5 V	Weigh	t 3.3 V	Weig	ht 5 V	Weigh	t 3.3 V
144 LQFP	100 LQFP	64 LQFP ²		SRC ³ = 0	SRC = 1	SRC = 0	SRC = 1	SRC = 0	SRC = 1	SRC = 0	SRC = 1
4	_		PG[2]	8%	12%	10%	10%	—	_	—	—
	4	3	PA[2]	8%	—	9%		8%		9%	—
		_	PE[0]	8%	_	9%	_		_	—	—
		3	PA[1]	7%	—	9%	_	7%	_	9%	—
		_	PE[1]	7%	10%	8%	9%	_	_	—	—
			PE[8]	7%	9%	8%	8%	—	_	—	—
			PE[9]	6%	—	7%				—	—
			PE[10]	6%		7%		_		—	
		3	PA[0]	5%	8%	6%	7%	5%	8%	6%	7%
		_	PE[11]	5%	_	6%	_	_	_	_	_
1	_	_	PG[9]	9%	—	10%	_	_	_	—	—
		_	PG[8]	9%		11%		_		—	
	1	—	PC[11]	9%	_	11%	_	_	_	_	_
		1	PC[10]	9%	13%	11%	12%	9%	13%	11%	12%
			PG[7]	10%	14%	11%	12%	_		—	—
	_	_	PG[6]	10%	14%	12%	12%			—	—
	1	1	PB[0]	10%	14%	12%	12%	10%	14%	12%	12%
			PB[1]	10%		12%		10%		12%	—
	_	—	PF[9]	10%	_	12%	_	_	_	_	_
		_	PF[8]	10%	15%	12%	13%	_	_	—	—
		_	PF[12]	10%	15%	12%	13%	—	_	—	—
	1	1	PC[6]	10%	—	12%		10%		12%	—
			PC[7]	10%	—	12%	_	10%	_	12%	—
	—	—	PF[10]	10%	14%	12%	12%			—	—
	—	_	PF[11]	10%		11%					
	1	1	PA[15]	9%	12%	10%	11%	9%	12%	10%	11%
	—	—	PF[13]	8%		10%				_	
	1	1	PA[14]	8%	11%	9%	10%	8%	11%	9%	10%
			PA[4]	8%	_	9%	_	8%	_	9%	_
			PA[13]	7%	10%	9%	9%	7%	10%	9%	9%
			PA[12]	7%		8%		7%		8%	

Table 24. I/O weight¹ (continued)

Example 1. No regulator (worst case)

The $|\Delta_{VDD(STDBY)}|$ parameter can be seen as the V_{DD} voltage drop through the ESR resistance of the regulator stability capacitor when the I_{DD_BV} current required to load V_{DD_LV} domain during the standby exit. It is thus possible to define the maximum equivalent resistance ESR_{STDBY}(MAX) of the total capacitance on the V_{DD} supply:

 $\text{ESR}_{\text{STDBY}}(\text{MAX}) = |\Delta_{\text{VDD}(\text{STDBY})}|/\text{I}_{\text{DD} \text{ BV}} = (30 \text{ mV})/(300 \text{ mA}) = 0.1\Omega^{-1}$

The dVDD(STDBY)/dt parameter can be seen as the V_{DD} voltage drop at the capacitance pin (excluding ESR drop) while providing the I_{DD_BV} supply required to load V_{DD_LV} domain during the standby exit. It is thus possible to define the minimum equivalent capacitance $C_{STDBY}(MIN)$ of the total capacitance on the V_{DD} supply:

 $C_{STDBY}(MIN) = I_{DD BV}/dVDD(STDBY)/dt = (300 mA)/(15 mV/\mu s) = 20 \mu F$

This configuration is a worst case, with the assumption no regulator is available.

Example 2. Simplified regulator

The regulator should be able to provide significant amount of the current during the standby exit process. For example, in case of an ideal voltage regulator providing 200 mA current, it is possible to recalculate the equivalent $ESR_{STDBY}(MAX)$ and $C_{STDBY}(MIN)$ as follows:

 $ESR_{STDBY}(MAX) = |\Delta_{VDD(STDBY)}|/(I_{DD BV} - 200 mA) = (30 mV)/(100 mA) = 0.3 \Omega$

 $C_{\text{STDBY}}(\text{MIN}) = (I_{\text{DD} BV} - 200 \text{ mA})/d\text{VDD}(\text{STDBY})/dt = (300 \text{ mA} - 200 \text{ mA})/(15 \text{ mV/}\mu\text{s}) = 6.7 \mu\text{F}$

In case optimization is required, $C_{\text{STDBY}}(\text{MIN})$ and $\text{ESR}_{\text{STDBY}}(\text{MAX})$ should be calculated based on the regulator characteristics as well as the board V_{DD} plane characteristics.

3.17.2 Low voltage detector electrical characteristics

The device implements a Power-on Reset (POR) module to ensure correct power-up initialization, as well as four low voltage detectors (LVDs) to monitor the V_{DD} and the V_{DD} LV voltage while device is supplied:

- POR monitors V_{DD} during the power-up phase to ensure device is maintained in a safe reset state (refer to RGM Destructive Event Status (RGM_DES) Register flag F_POR in device reference manual)
- LVDHV3 monitors V_{DD} to ensure device reset below minimum functional supply (refer to RGM Destructive Event Status (RGM_DES) Register flag F_LVD27 in device reference manual)
- LVDHV5 monitors V_{DD} when application uses device in the 5.0 V ± 10% range (refer to RGM Functional Event Status (RGM_FES) Register flag F_LVD45 in device reference manual)
- LVDLVCOR monitors power domain No. 1 (refer to RGM Destructive Event Status (RGM_DES) Register flag F_LVD12_PD1 in device reference manual
- LVDLVBKP monitors power domain No. 0 (refer to RGM Destructive Event Status (RGM_DES) Register flag F_LVD12_PD0 in device reference manual)

NOTE

When enabled, power domain No. 2 is monitored through LVDLVBKP.

^{1.} Based on typical time for standby exit sequence of 20 µs, ESR(MIN) can actually be considered at ~50 kHz.

Symbol		C Parameter		Conditions ¹		Value			Unit
		C	Falameter	Conditions	litions -		Тур	Мах	
I _{DDMAX} ²	СС	D	RUN mode maximum average current	_		_	115	140 ³	mA
I _{DDRUN} 4	СС	Т	RUN mode typical	f _{CPU} = 8 MHz		_	7	_	mA
		Т	average current ⁵	f _{CPU} = 16 MHz		—	18	_	-
		Т		f _{CPU} = 32 MHz			29		
		Ρ		f _{CPU} = 48 MHz		_	40	100	
		Ρ		f _{CPU} = 64 MHz		_	51	125	
I _{DDHALT}	СС	С	HALT mode current ⁶	Slow internal RC oscillator	T _A = 25 °C	_	8	15	mA
		Ρ		(128 kHz) running	T _A = 125 °C	_	14	25	
IDDSTOP	СС	Ρ	STOP mode current ⁷	Slow internal RC oscillator	T _A = 25 °C	_	180	700 ⁸	μA
		D			T _A = 55 °C	_	500	_	
		D			T _A = 85 °C	_	1	6 ⁸	mA
		D			T _A = 105 °C	_	2	9 ⁸	
		Ρ			T _A = 125 °C	-	4.5	12 ⁸	
I _{DDSTDBY2}	СС	Ρ		Slow internal RC oscillator	T _A = 25 °C	_	30	100	μA
		D	current ⁹	(128 kHz) running	T _A = 55 °C	-	75		
		D			T _A = 85 °C	-	180	700	
		D			T _A = 105 °C	_	315	1000	
		Ρ			T _A = 125 °C	-	560	1700	
I _{DDSTDBY1}	СС	Т		Slow internal RC oscillator	T _A = 25 °C	-	20	60	μA
		D	current ¹⁰	(128 kHz) running	T _A = 55 °C	-	45		
		D			T _A = 85 °C	_	100	350	
		D			T _A = 105 °C	_	165	500	
		D			T _A = 125 °C		280	900	

Table 28. Power consumption on VDD_BV and VDD_HV
--

 $\frac{1}{1}$ V_{DD} = 3.3 V ± 10% / 5.0 V ± 10%, T_A = -40 to 125 °C, unless otherwise specified

² I_{DDMAX} is drawn only from the V_{DD_BV} pin. Running consumption does not include I/Os toggling which is highly dependent on the application. The given value is thought to be a worst case value with all peripherals running, and code fetched from code flash while modify operation ongoing on data flash. Notice that this value can be significantly reduced by application: switch off not used peripherals (default), reduce peripheral frequency through internal prescaler, fetch from RAM most used functions, use low power mode when possible.

³ Higher current may be sinked by device during power-up and standby exit. Please refer to in rush current on Table 26.

- ⁴ I_{DDRUN} is drawn only from the V_{DD_BV} pin. RUN current measured with typical application with accesses on both flash and RAM.
- ⁵ Only for the "P" classification: Data and Code Flash in Normal Power. Code fetched from RAM: Serial IPs CAN and LIN in loop back mode, DSPI as Master, PLL as system Clock (4 x Multiplier) peripherals on (eMIOS/CTU/ADC) and running at max frequency, periodic SW/WDG timer reset enabled.

Package pinouts and signal descriptions

Symbol		с	Parameter	Conditions ¹		Value			Unit
		Ŭ	i didiletti			Min	Тур	Мах	
I _{FIRCSTOP}	СС		Fast internal RC oscillator high	T _A = 25 °C	sysclk = off	_	500		μA
			frequency and system clock current in stop mode		sysclk = 2 MHz	_	600	_	
					sysclk = 4 MHz	—	700	_	
					sysclk = 8 MHz	—	900	_	
					sysclk = 16 MHz	—	1250	_	
t _{FIRCSU}	СС		Fast internal RC oscillator start-up time	V _{DD} = 5.0 V ± 10%			1.1	2.0	μs
$\Delta_{FIRCPRE}$	СС	Т	Fast internal RC oscillator precision after software trimming of f _{FIRC}	T _A = 25 °C		-1		+1	%
	СС	Т	Fast internal RC oscillator trimming step	T _A = 25 °C			1.6		%
$\Delta_{FIRCVAR}$	CC	Ρ	Fast internal RC oscillator variation in overtemperature and supply with respect to f_{FIRC} at $T_A = 25$ °C in high-frequency configuration	_		-5		+5	%

 Table 42. Fast internal RC oscillator (16 MHz) electrical characteristics (continued)

 $\overline{^{1}}$ V_{DD} = 3.3 V \pm 10% / 5.0 V \pm 10%, T_A = -40 to 125 °C, unless otherwise specified.

² This does not include consumption linked to clock tree toggling and peripherals consumption when RC oscillator is ON.

3.25 Slow internal RC oscillator (128 kHz) electrical characteristics

The device provides a 128 kHz slow internal RC oscillator. This can be used as the reference clock for the RTC module.

Table 43. Slow internal RC oscillator (128 kHz) electrical characteristics

Symbol	ool		Symbol C Parameter		Parameter	Conditions ¹	Value			Unit
Cymbol		C Faidlielei		Conditione	Min	Тур	Мах			
f _{SIRC}	СС	Ρ	Slow internal RC oscillator low	T _A = 25 °C, trimmed		128		kHz		
	SR		frequency	_	100		150			
I _{SIRC} ^{2,}	СС	С	Slow internal RC oscillator low frequency current	T _A = 25 °C, trimmed	I	_	5	μA		
t _{SIRCSU}	СС	Ρ	Slow internal RC oscillator start-up time	$T_A = 25 \text{ °C}, V_{DD} = 5.0 \text{ V} \pm 10\%$		8	12	μs		
$\Delta_{SIRCPRE}$	СС	С	Slow internal RC oscillator precision after software trimming of f _{SIRC}	T _A = 25 °C	-2		+2	%		
	СС	С	Slow internal RC oscillator trimming step	_	_	2.7	-			
ASIRCVAR	CC	С	Slow internal RC oscillator variation in temperature and supply with respect to f_{SIRC} at $T_A = 55$ °C in high frequency configuration	High frequency configuration	-10		+10	%		

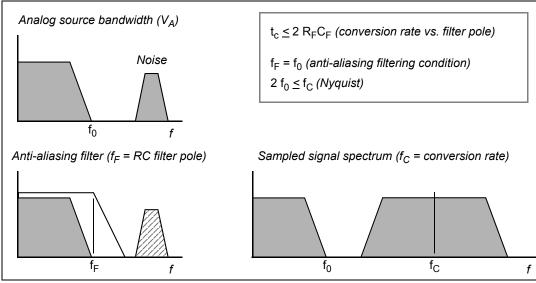


Figure 23. Spectral representation of input signal

Calling f_0 the bandwidth of the source signal (and as a consequence the cut-off frequency of the anti-aliasing filter, f_F), according to the Nyquist theorem the conversion rate f_C must be at least $2f_0$; it means that the constant time of the filter is greater than or at least equal to twice the conversion period (t_c). Again the conversion period t_c is longer than the sampling time t_s , which is just a portion of it, even when fixed channel continuous conversion mode is selected (fastest conversion rate at a specific channel): in conclusion it is evident that the time constant of the filter R_FC_F is definitively much higher than the sampling time t_s , so the charge level on C_S cannot be modified by the analog signal source during the time in which the sampling switch is closed.

The considerations above lead to impose new constraints on the external circuit, to reduce the accuracy error due to the voltage drop on C_S ; from the two charge balance equations above, it is simple to derive Equation 11 between the ideal and real sampled voltage on C_S :

$$\frac{V_{A2}}{V_{A}} = \frac{C_{P1} + C_{P2} + C_{F}}{C_{P1} + C_{P2} + C_{F} + C_{S}}$$

Eqn. 11

From this formula, in the worst case (when V_A is maximum, that is for instance 5 V), assuming to accept a maximum error of half a count, a constraint is evident on C_F value:

Eqn. 12

$$C_F > 2048 \bullet C_S$$

Package characteristics

4.1.2 100 LQFP

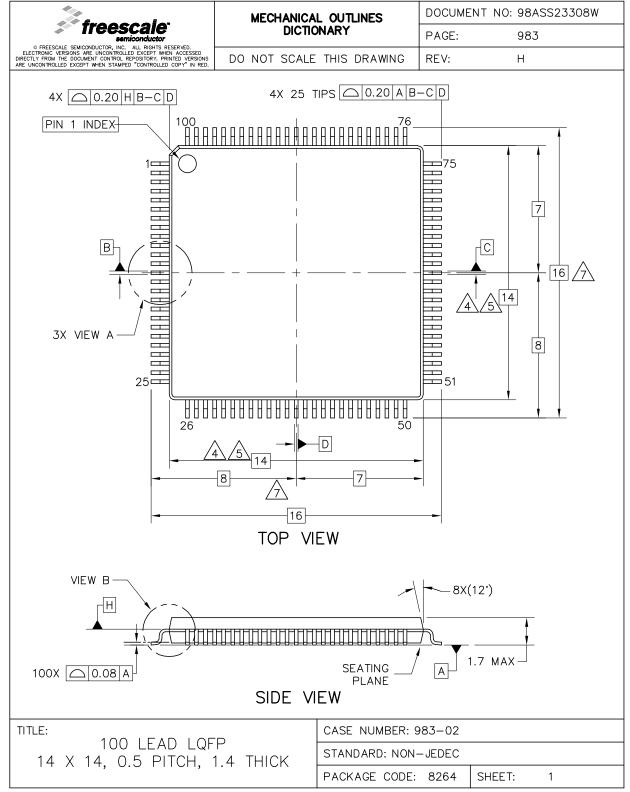


Figure 38. 100 LQFP package mechanical drawing (1 of 3)

MPC5604B/C Microcontroller Data Sheet, Rev. 11

Package characteristics

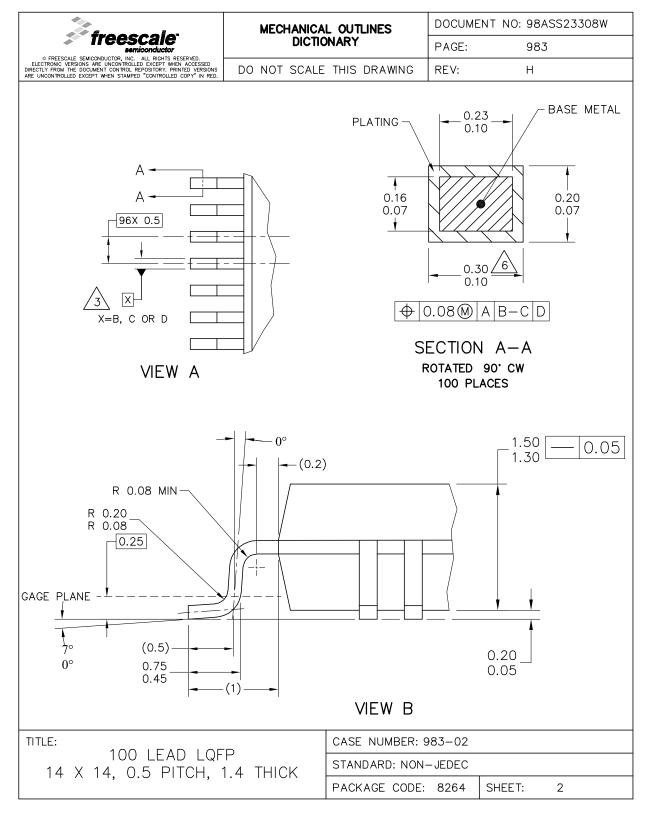


Figure 39. 100 LQFP package mechanical drawing (2 of 3)

MPC5604B/C Microcontroller Data Sheet, Rev. 11

Package characteristics

	MECHANICA	L OUTLINES	DOCUMENT NO: 98ASS23308					
	DICTIONARY		PAGE:	983				
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NOTES:			1					
1. ALL DIMENSIONS ARE IN MILL	IMETERS.							
2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.								
$\sqrt{3}$ datums b, c and d to be determined at datum plane H.								
THE TOP PACKAGE BODY SIZ BY A MAXIMUM OF 0.1 MM.	THE TOP PACKAGE BODY SIZE MAY BE SMALLER THAN THE BOTTOM PACKAGE SIZE							
5. DIMENSIONS DO NOT INCLUDE PROTRUSION IS 0.25 mm PE SIZE DIMENSIONS INCLUDING	ER SIDE. THE DIMI							
6. DIMENSION DOES NOT INCLUDE DAM BAR PROTRUSION. PROTRUSIONS SHALL NOT CAUSE THE LEAD WIDTH TO EXCEED 0.35. MINIMUM SPACE BETWEEN PROTRUSION AND AN ADJACENT LEAD SHALL BE 0.07 MM.								
7. dimensions are determined	AT THE SEATING	G PLANE, DATUM	A.					
TITLE:		CASE NUMBER: S	983-02					
100 LEAD LQF 14 X 14, 0.5 PITCH,		STANDARD: NON-JEDEC						
$\begin{bmatrix} 14 \land 14, 0.5 \ \Box \square, \end{bmatrix}$	1.+ 1111UN	PACKAGE CODE:	8264	SHEET: 3				

Figure 40. 100 LQFP package mechanical drawing (3 of 3)

MPC5604B/C Microcontroller Data Sheet, Rev. 11

4.1.3 144 LQFP

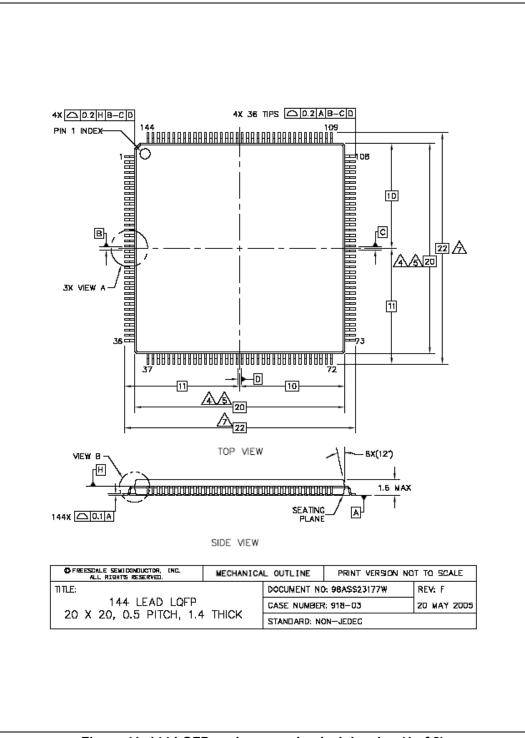
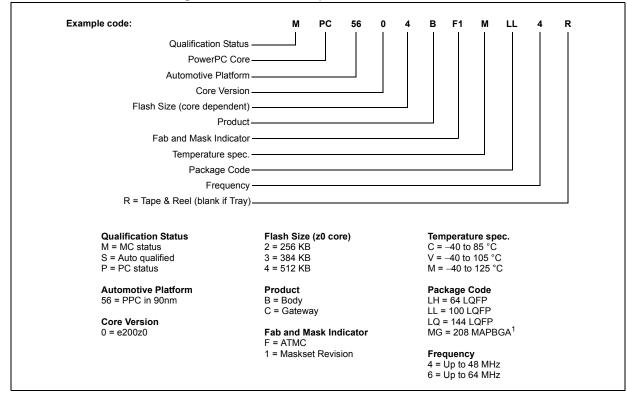


Figure 41. 144 LQFP package mechanical drawing (1 of 2)

5 Ordering information

Figure 45. Commercial product code structure



¹ 208 MAPBGA available only as development package for Nexus2+

6 Document revision history

Table 50 summarizes revisions to this document.

Table 50. Revision history

Revision	Date	Description of Changes
1	04-Apr-2008	Initial release.

Document revision history

Revision	Date	Description of Changes
2	06-Mar-2009	Made minor editing and formatting changes to improve readability Harmonized oscillator naming throughout document Features: —Replaced 32 KB with 48 KB as max SRAM size —Updated description of INTC —Changed max number of GPIO pins from 121 to 123 Updated Section 1.2, Description Updated Table 2 Added Section 2, Block diagram Section 3, Package pinouts and signal descriptions: Removed signal descriptions (these are found in the device reference manual) Updated Figure 5: —Replaced VPP with VSS_HV on pin 18 —Added MA[1] as AF3 for PC[3] (pin 116) —Changed description for pin 120 to PH[10] / GPIO[122] / TMS —Added MA[0] as AF2 for PC[3] (pin 116) —Changed description for pin 120 to PH[9] / GPIO[121] / TCK —Replaced VPP with VSS_HV on pin 14 —Added MA[1] as AF3 for PC[3] (pin 77) —Changed description for pin 8 to PH[9] / GPIO[122] / TMS —Added MA[1] as AF3 for PC[3] (pin 77) —Changed description for pin 8 to PH[9] / GPIO[121] / TCK —Replaced NMI[0] with NMI on pin 7 Updated Figure 6: —Changed description for ball B8 from TCK to PH[9] —Changed description for ball B9 from TMS to PH[10] —Updated Gescription for ba

Table 50. Revision history (continued)

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